

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	8629	(measur\$3 or detect\$3) near9 (film near4 substrate)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:11
L2	19	1 and mold\$3 and imprint\$3 near layer	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:25
L3	48	1 and mold\$3 and imprint\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 12:58
L4	74	1 and mold\$3 and (area or region) near6 (film near4 substrate)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:04
L5	35	4 and defects	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 12:59
L6	74	1 and mold\$3 near4 ((device or unit) or apparatus)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:08
L7	16	6 and (area or region) near6 (film near4 substrate)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:04
L8	33	6 and (area or region) near6 (substrate)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:07
L9	1	6 and "430"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:07
L10	6219	1 and mold\$3 ahnd sensor near9 defect	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:08

L11	1	1 and mold\$3 and sensor near9 defect	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:09
L12	194	1 and mold\$3 and sensor	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:09
L13	17	1 and mold\$3 and print near2 (sensor or head)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:10
L14	26	12 and imprint\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:10

L11	1	1 and mold\$3 and sensor near9 defect	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:09
L12	194	1 and mold\$3 and sensor	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:09
L13	17	1 and mold\$3 and print near2 (sensor or head)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:10
L14	26	12 and imprint\$3	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:10
L15	140	(measur\$3 or detect\$3) near9 (defects near6 (film near4 substrate))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:12
L16	0	stack near defect and 15	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:12
L17	0	template near defect and 15	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:13
L18	55	template near defect	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:13
L19	13	18 and "430"/\$.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:14
L20	3	1 and subset near6 (region or area)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:16

L21	123	1 and subset	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:16
L22	87	(Board near1 Regents) near1 (University near1 Texas)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:20
L23	39	Bailey near Todd	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/07/10 13:26